

<b>Notice of References Cited</b>	Application/Control No. 10/617,319	Applicant(s)/Patent Under Reexamination KLUBEK ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0004215	01-2004	Iechi et al.	257/40
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	O	JP 2000021574	01-2000	Japan	Ueno et al.	----
	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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